

Quantum Coherence Lab Zumbühl Group

Single and Double Hole Quantum Dots in Strained Ge/SiGe quantum wells

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Motivation

- Silicon as a leading contender for hosting spin-based qubits
 - Long coherence times, isotropic enrichment, CMOS processing
 - Si/SiGe heterostructures with low disorder interface
 - Material related issues, e.g large variation of the valley splitting $(35 270 \,\mu\text{eV})$ [1]
- Ge/SiGe heterostructures
 - Holes as dominant charge carriers -> p-type orbital characters, suppresses qubit decoherence via hyperfine
 - Large heavy-hole and light-hole band splitting (up to 100 meV) -> results from confinement and strain [2]
 - Heavy-hole ground state has no degenerate states
 - EDSR possible due to large cubic Rashba spin-orbit coupling strength -> simplified device design
 - Large g-factor (up to $g \sim 28$)
- In this paper
 - Single and double quantum dots in planar Ge/SiGe using a single layer gate layout
 - Hole effective mass of $m^* \sim 0.08 \ m_0$

Device and Heterostructure



[1] Su et al., Phys Rev Mat. 1 044601 (2017) [2] Laroche et al., APL 108, 233504 (2016)

Hall Bar Measurements I

- Longitudinal and Hall resistance measured in 4He cryostat with variable tempereture
- Mean free path from mobility measurements
 - $\mu \ge 6 \times 10^4 \text{ cm}2/\text{Vs}$
 - High quality samples, low disorder



Hall Bar Measurements II

- Magnetoresistance data reveals Shubnikov-de Haas oscillations
 - Shows low disorder of material
 - Inverse proportional to temperature
- Extract amplitudes of even filling factor and trace temperature dependence to extract effective mass at various densities

$$\Delta R_{\chi\chi} \propto \frac{2\pi^2 \frac{k_B T}{\Delta E}}{\sinh \left[2\pi^2 \frac{k_B T}{\Delta E}\right]}$$

with $\Delta E = heB/2\pi m^*$

- Yields a hole effective mass of $m^* \sim 0.08 m_0$
 - Note: electron effective mass in GaAs: $m^* \sim 0.067 m_0$
- Large spacial extent -> enhanced tunnel couplings, facilitation of qubit-qubits interaction, larger lithography



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- Measurements performed in dilution refridgerator ($T \sim 30 \text{ mK}$)
- Accumulation gates: -0.4 -1.6 V; AC bias: 100 μ V at 1333 Hz
- CPU fixed, RISO and RPU sweep -> diagonal lines visible
 - Coulomb oscillations corresponding to removal of individual holes
- Broadening due to highly transparent tunnel barriers, not experimental parameters (temperature, voltage bias, ...)
 - Excludes possibility to see excited states
 - Consistent with simulations (later slides)

Single Dot I





- CPU and RISO fixed, SD and RPU sweep -> Coulomb diamonds
- Diamonds widen -> increasing charging energy -> low occupancy regime
- Capacitance $C_{tot} = \frac{Q}{V} = 92.8 \text{ aF}$ (with V extracted Coulomb oscillation period)

> Charging energy
$$E_c = \frac{e^2}{C_{tot}} = 1.7 \text{ meV}$$

Consistent with height of Coulomb diamonds

Single Dot II





- Device tuneable into double dot regime
 - Visible in stability diagram
- Note: no additional voltage needed on CPU, potential landscape imposed by AGU naturally forms dot

Double Dots



Simulation

- Simulation of device with parameters extracted from SEM images, material stack thickness and dielectric properties
- Gates voltages comparable to actual device (except CPU -> trapped charge in real device)
- Simulation reveals
 - Oblong island -> quantum dot
 - Rapid transition from no charge accumulation to a flooded situation without charge confinement
 - Only few holes possible -> shallow potential
- Further simulations of capacitance -> reasonable agreement with measured capacitances
 - Dot on real device has similar lateral extent



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Conclusion

- Demonstration of single and double hole quantum dots in a Ge/SiGe heterostructure with a single gate layer
- Design similar to Si/SiGe systems
 - Allows direct comparison
- Hall measurement reveal hole effective mass of $m^* \sim 0.08 m_0$
 - Similar to GaAs electron effective mass (0.067 m₀)
 - Large wavefunction



